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A decorative grey line on the left side of the slide, starting with a sharp peak and then settling into a wavy horizontal line.

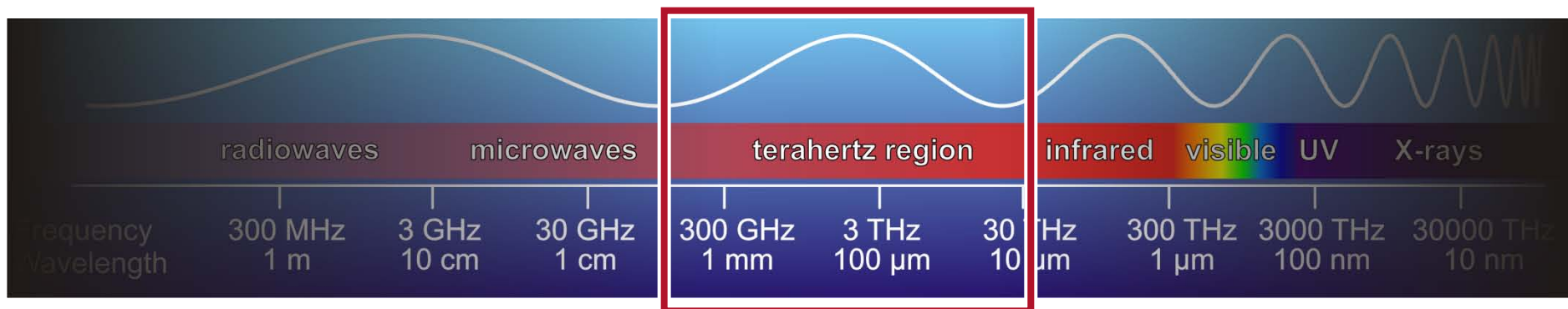
Ultrabroadband, time-resolved THz spectroscopy of disordered materials

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Technical University of Denmark
DK-2800 Kongens Lyngby, Denmark



- Single-cycle, ultrabroadband light at long wavelengths
- Time-resolved THz spectroscopy
- AC conductivity: Drude and non-Drude response
 - Silicon nanoparticles
 - Polymer solar cells
- Adiabatic field compression to MV/cm field strengths





Early prediction of THz technology

..."Get to the point man. V

"Ah me, these excitable, h
to make a type of low-p
frequency, it used far in
could possibly see, how

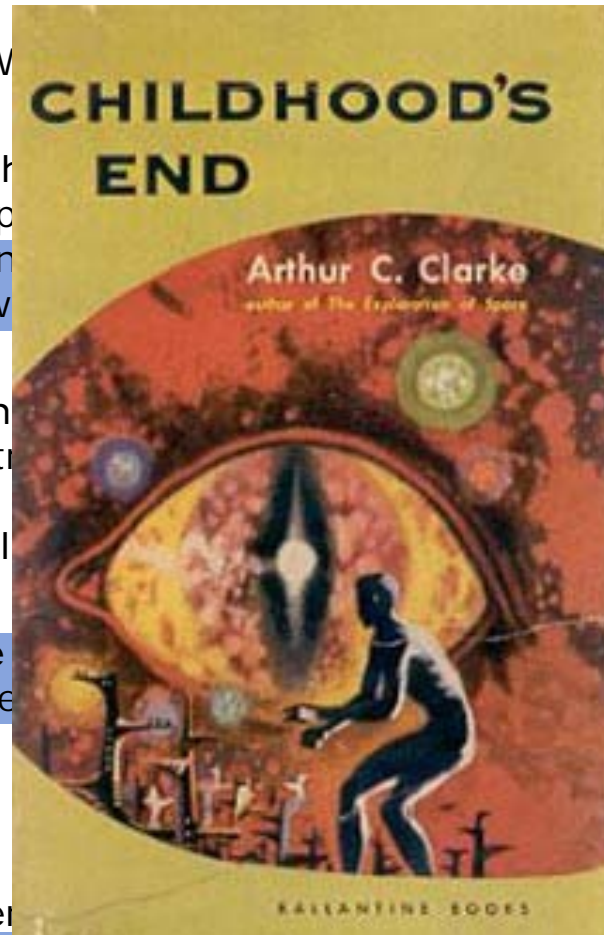
..."We've proved that th
is about three centimet
We couldn't detect any
low power which was al

He pushed across a piece
one spot was a kink like

"See that little kink?"

"Yes, what is it?"

"Only Karellen [the alien
might even have calculated his size."



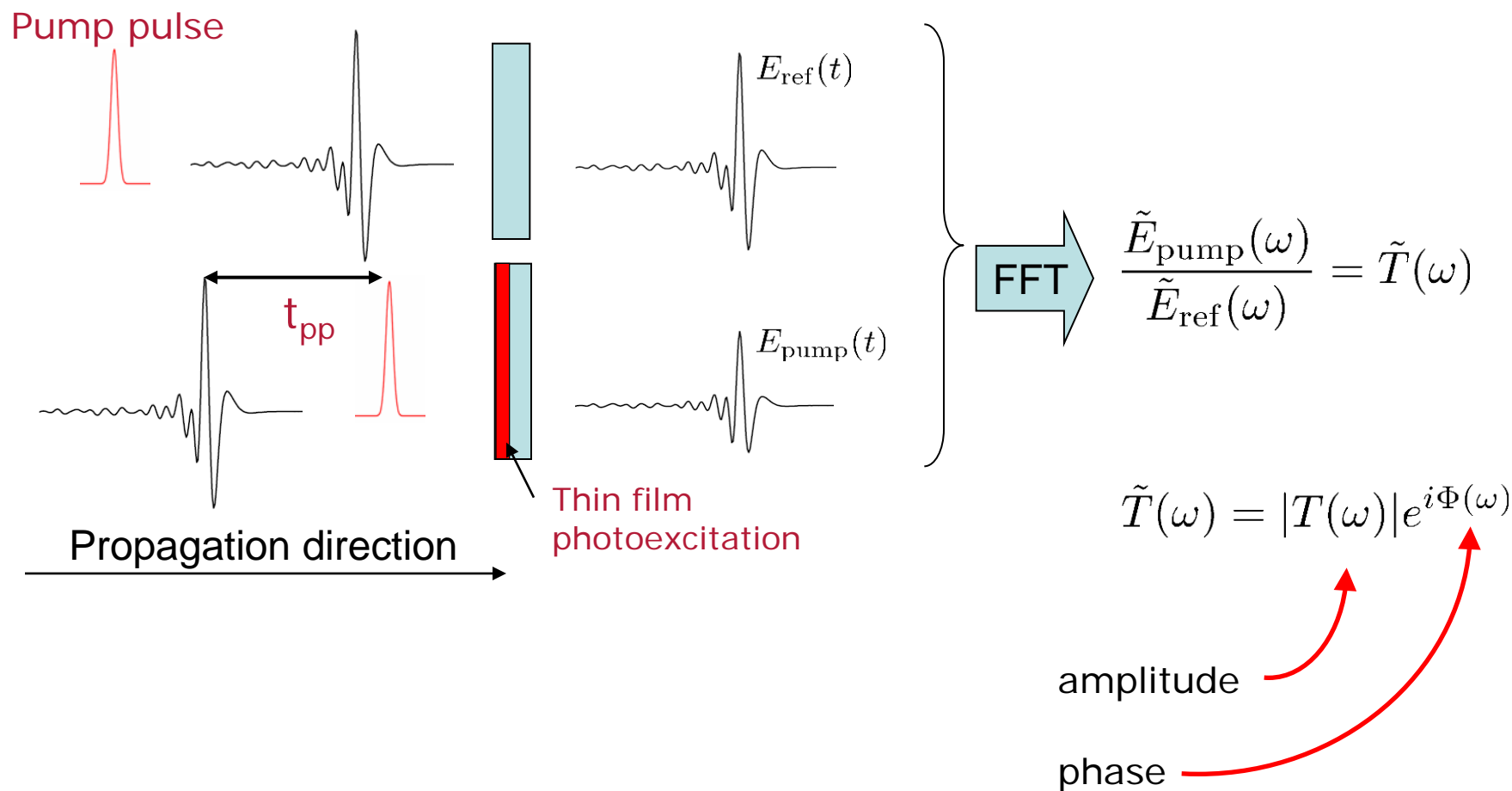
ed Duval. "What we did was
waves of very high
n we were sure no creature

screen of yours. The screen
s at least ten meters across.
ardly expected to with the
did get *this*."

was a single wavy line. In
quake.

had been a bit better, we

Time-resolved Terahertz Spectroscopy (TRTS)





Extraction of spectroscopic data

THz-TDS raw data:

$$E_{ref}(t), E_{pump}(t) \xrightarrow{\text{FFT}} E_{ref}(\omega), E_{pump}(\omega) \xrightarrow{\quad} \begin{aligned} T(\omega) &= \frac{|E_{pump}(\omega)|}{|E_{ref}(\omega)|} \\ \Theta(\omega) &= \theta_{pump} - \theta_{ref} \end{aligned}$$

Transmission amplitude and phase

Transmission amplitude and phase are then used to calculate optical properties;

$$\hat{n} = n + i\kappa, \quad \hat{\epsilon} = \epsilon' + i\epsilon'', \quad \Delta\hat{\sigma} = \Delta\sigma' + i\Delta\sigma''$$

Photoexcited charge carriers in semiconductors are best described by their conductivity:

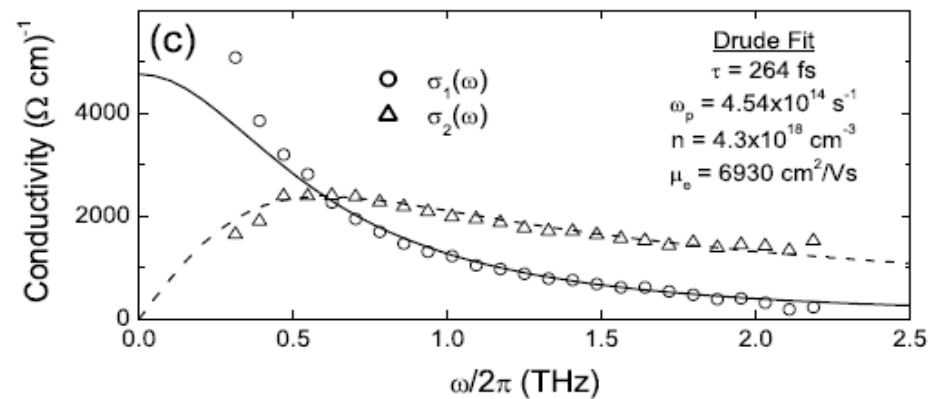
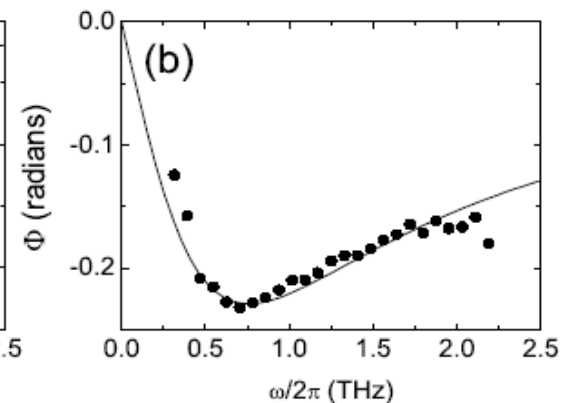
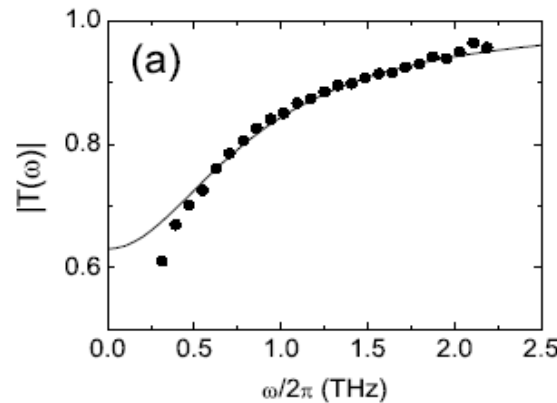
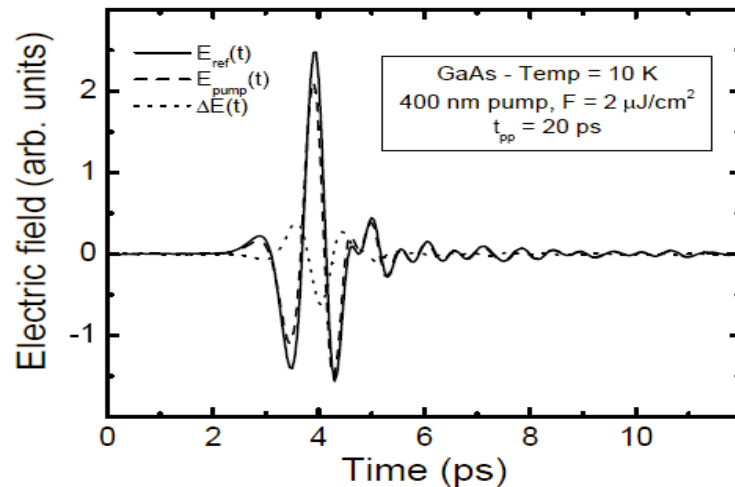
$$\Delta\sigma'_s(\omega) = \frac{N+1}{Z_0} \left[\frac{1}{|T(\omega)|} \cos[\Phi(\omega)] - 1 \right]$$

$$\Delta\sigma''_s(\omega) = -\frac{N+1}{Z_0} \left[\frac{1}{|T(\omega)|} \sin[\Phi(\omega)] \right]$$

Thin film approximation: Tinkham equations for photoexcited carriers



3D: Photoexcited GaAs

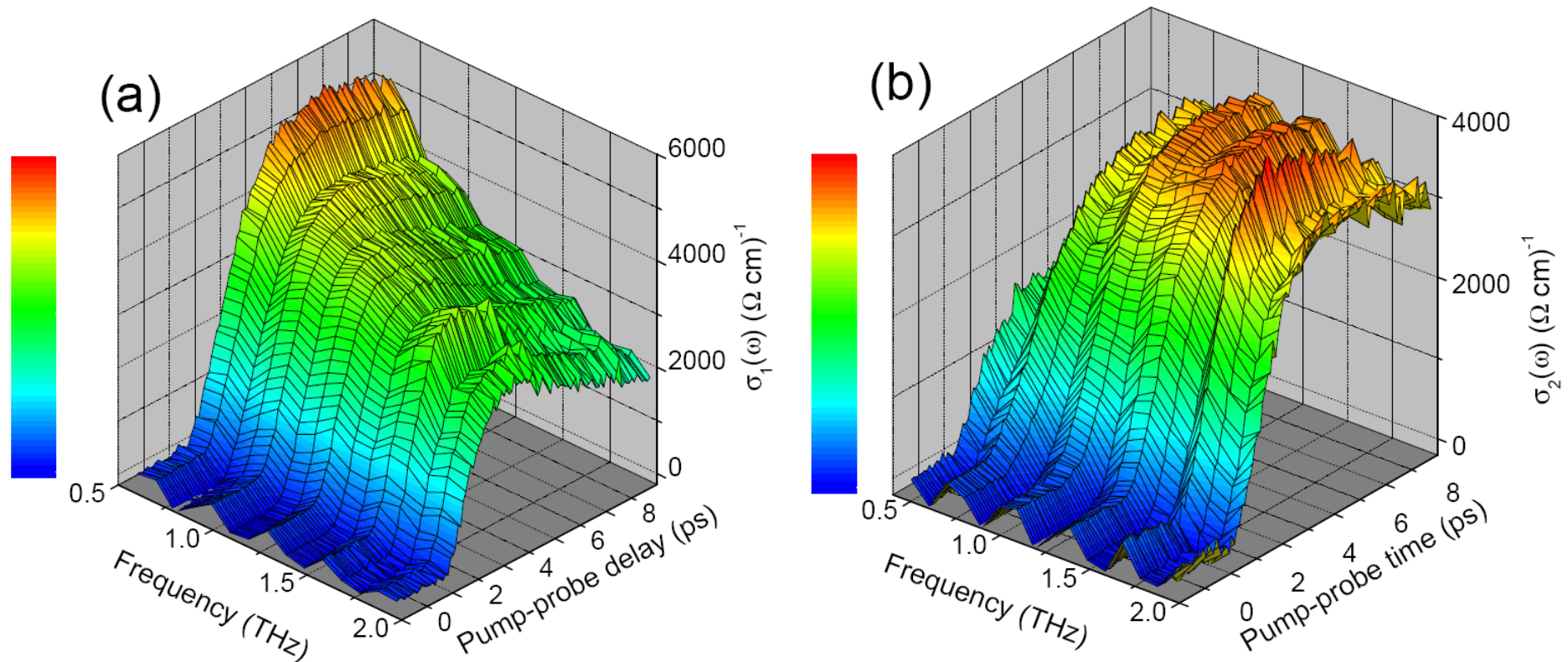


Carriers in GaAs are well described by Drude model just picoseconds after photoinjection.

$$\hat{\sigma}(\omega) = \frac{Ne^2\tau}{m} \frac{1}{1 - i\omega\tau}$$



Time-dependent Drude parameters

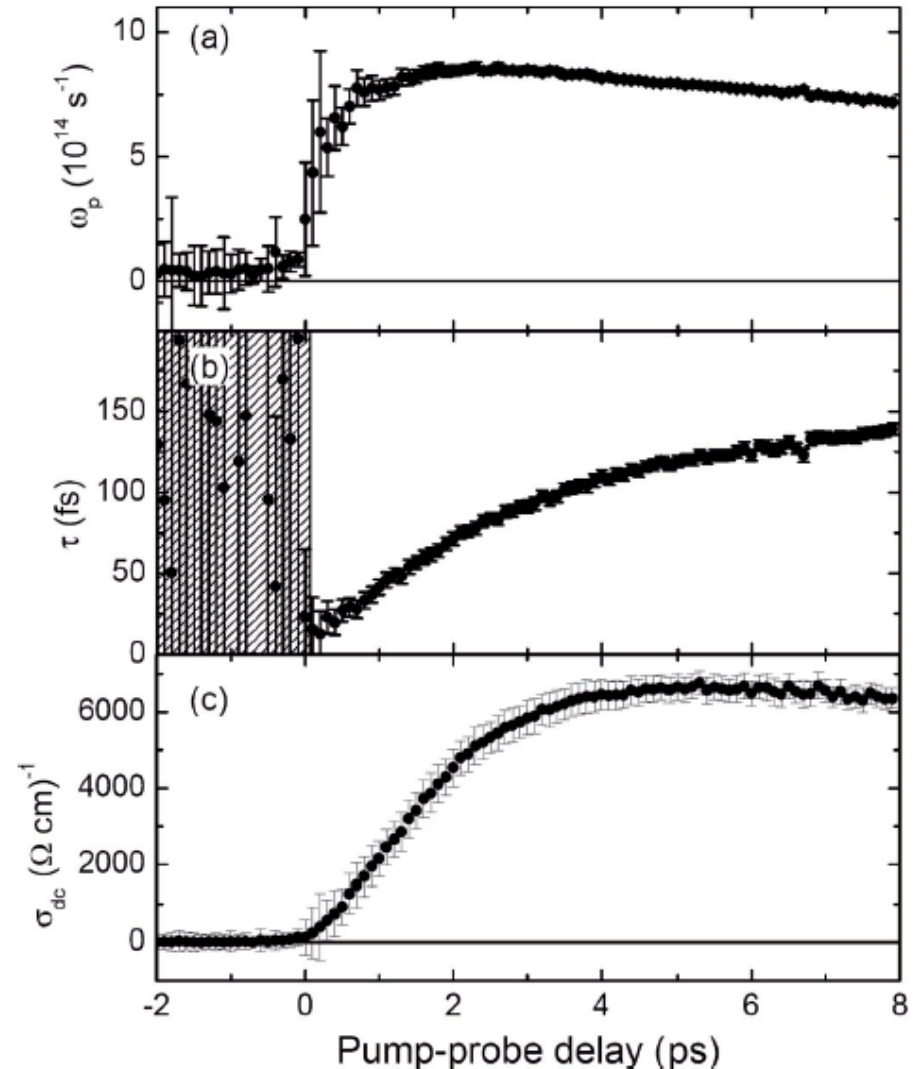


- Fit Drude model expression to data for increasing delay t_{pp}
- Time dependence of the Drude parameters
- Example: semi-insulating GaAs excited @ 400 nm



Time-dependent Drude parameters

- Fit Drude model expression to data for increasing delay t_{pp}
- Time dependence of the Drude parameters
- Example: semi-insulating GaAs excited @ 400 nm
- Parameter extraction reveals the (here: known) carrier dynamics
- Instant rise of plasma frequency
- Slower rise of scattering time
- Slower rise of DC conductivity

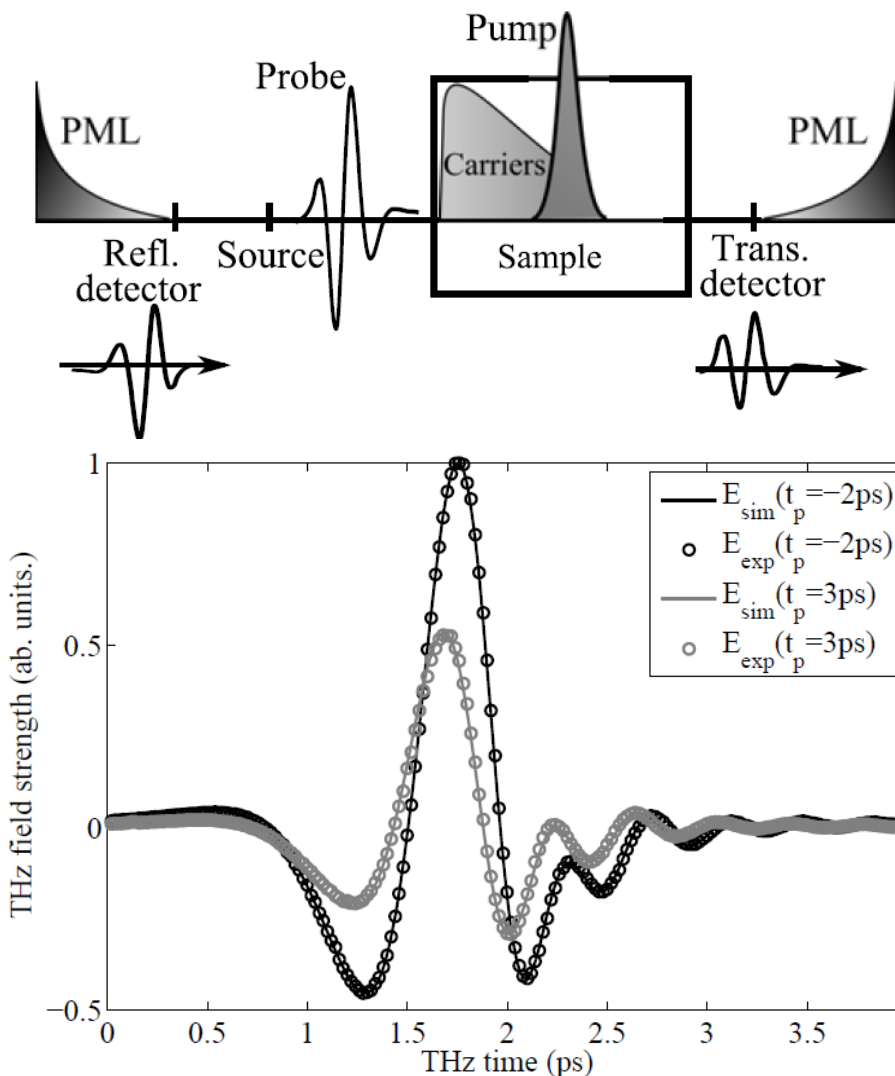




FDTD simulation of TRTS



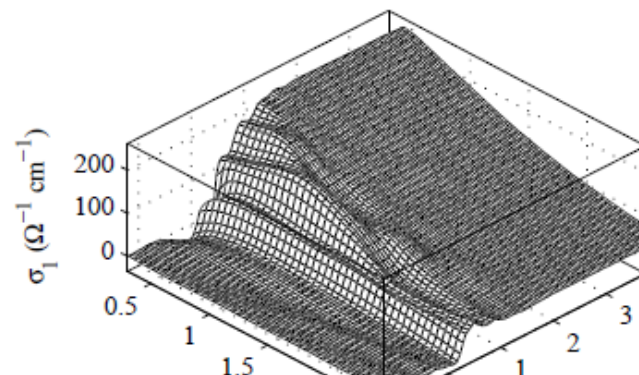
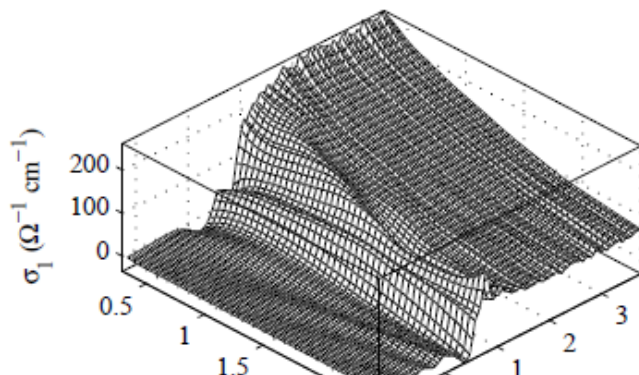
- In some situations the simple Fourier transform spectroscopy approach is not sufficient to understand the THz-TDS data
- Time-resolved spectroscopy near $t_{pp} = 0$
- Diffusion of charges in the sample during measurement
- Master student Casper Larsen coded a TRTS experiment in FDTD
- Thorough comparison between FDTD and experiment
- GaAs, 800 and 400 nm excitation
- Carrier dynamics explicitly included in code
- Full description of dispersion, diffraction, phase mismatch





Simulation vs experiment

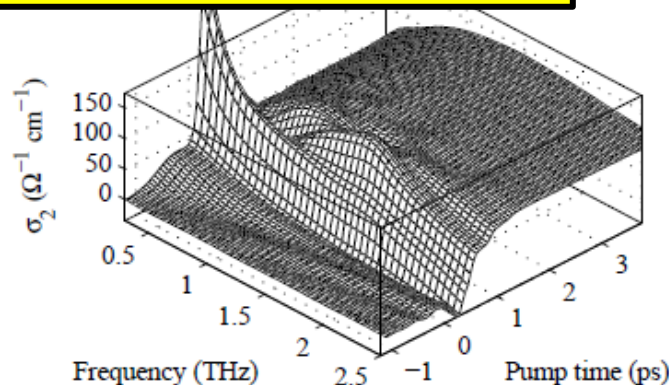
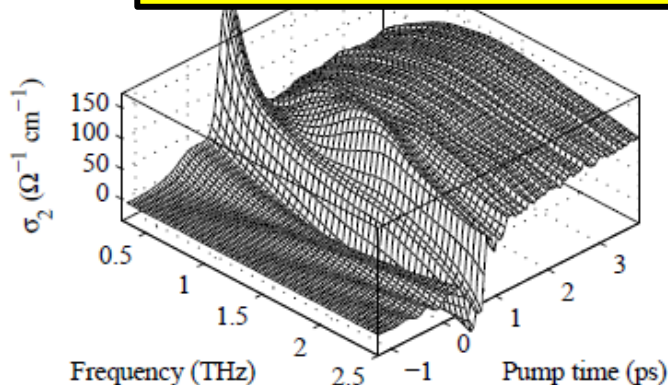
$$\sigma_1(\omega, t_{pp})$$



FDTD simulation tool available at
www.terahertz.dk

7 $\mu\text{J}/\text{cm}^2$
800 nm
45 fs

$$\sigma_2(\omega, t_{pp})$$

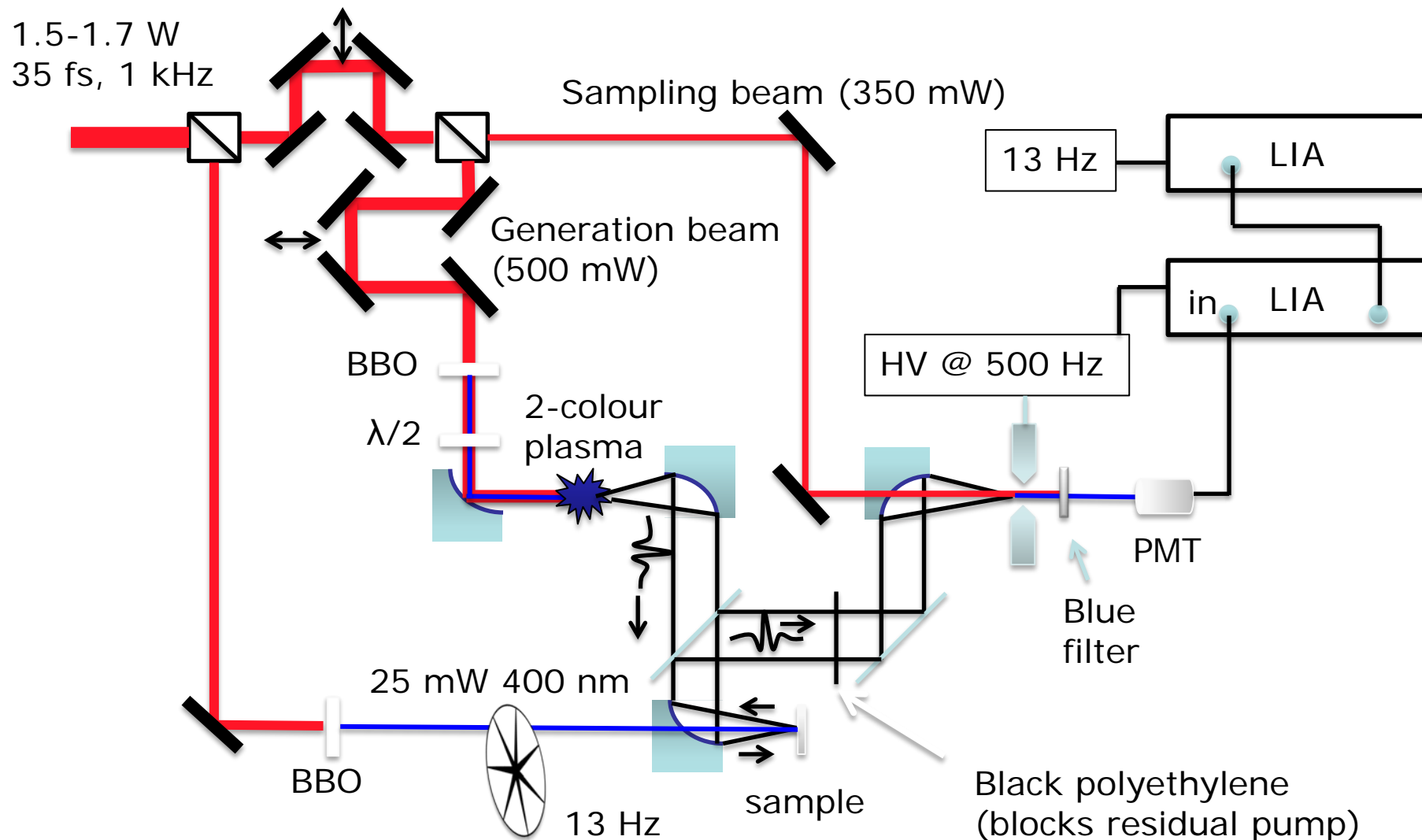


(a) Experiment

(b) Detector and aperture



Air Plasma Time-resolved THz Spectrometer

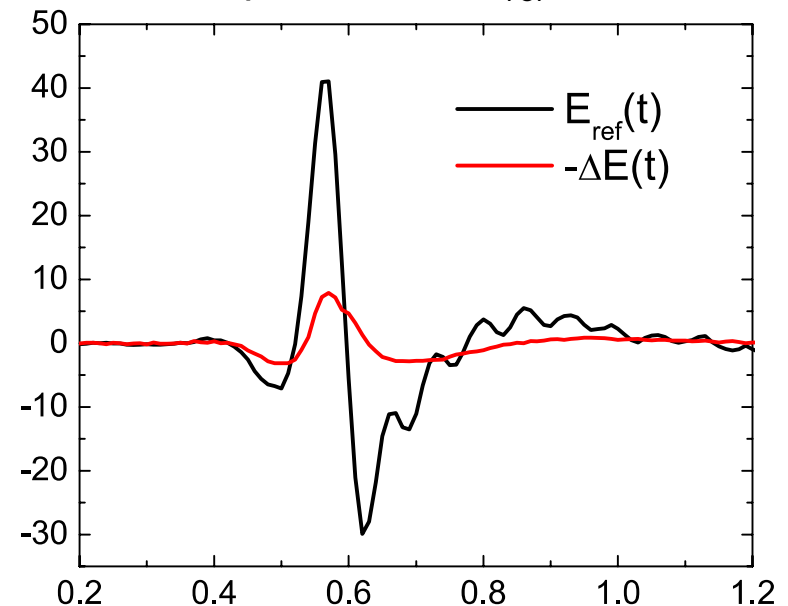
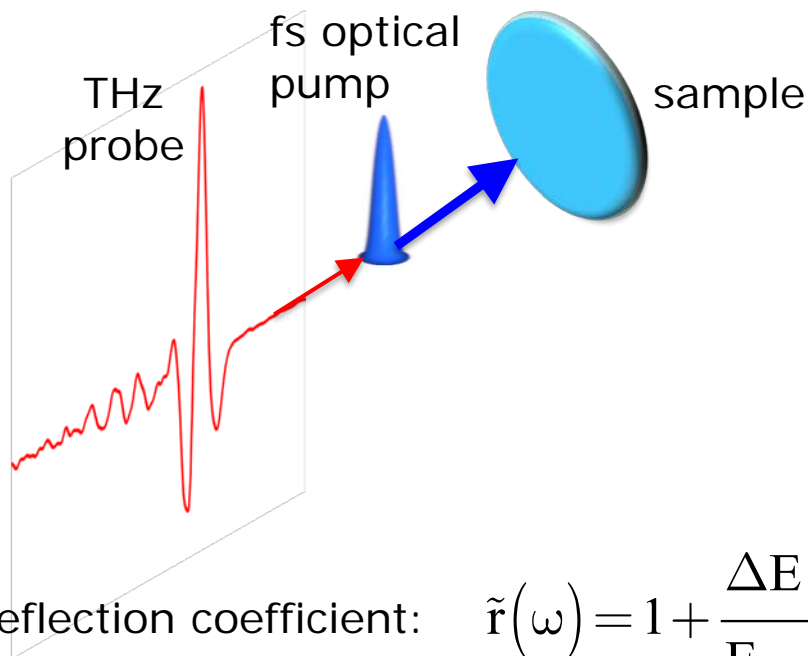




Experiment in reflection

- 400 nm pump – THz probe
- $F_{400\text{nm}} = 800 \mu\text{J}/\text{cm}^2$

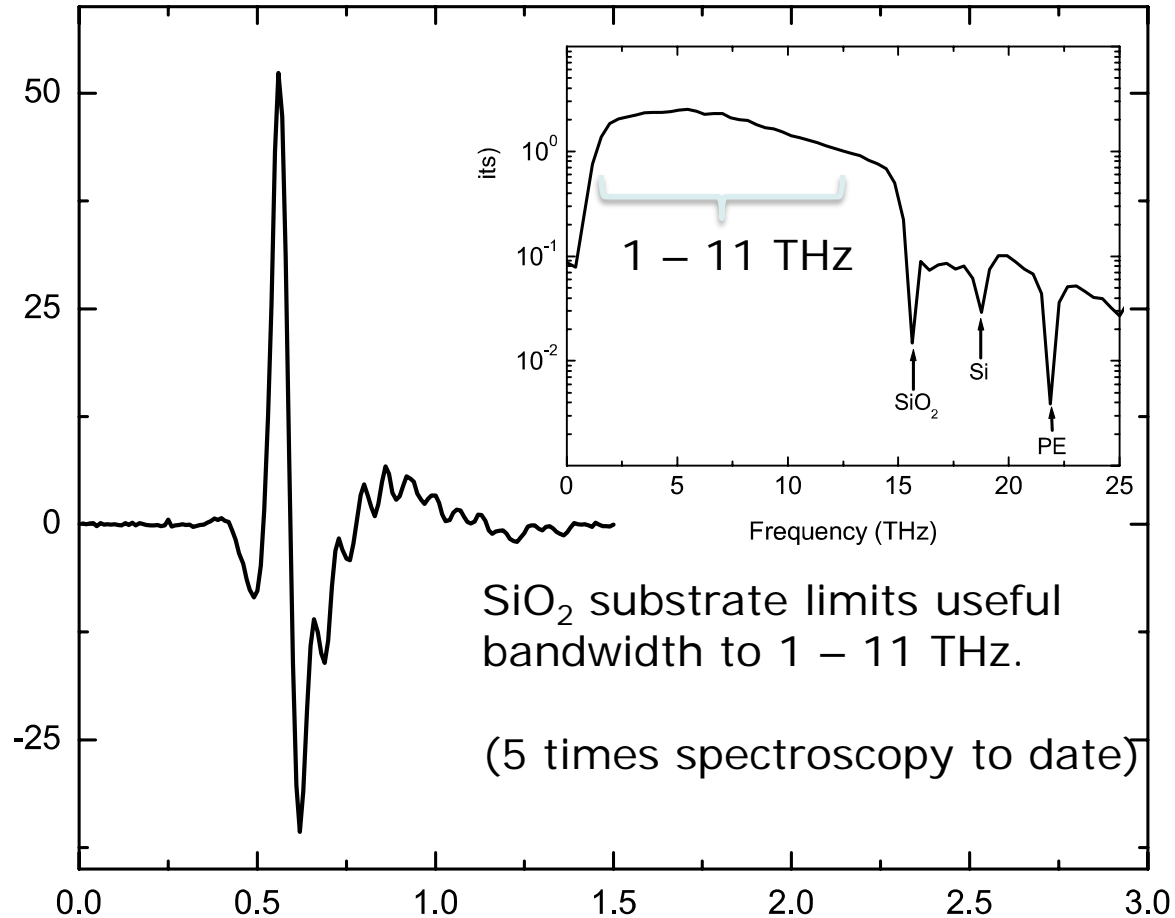
Simultaneous acquisition of $E_{\text{ref}}(t)$ and $-\Delta E(t)$



Reflection coefficient:
$$\tilde{r}(\omega) = 1 + \frac{\Delta E(\omega)}{E_{\text{ref}}(\omega)} = \frac{1 - n(\omega) - Z_0 d \tilde{\sigma}(\omega)}{1 + n(\omega) + Z_0 d \tilde{\sigma}(\omega)} \left\{ \frac{1 + n(\omega)}{1 - n(\omega)} \right\}$$



Spectrometer performance





Drude and non-Drude conductivity

- Drude model:
Mean free path $l = v_F \tau$ (Fermi velocity)
- What could happen if carriers are confined to $d < l$
- Enhanced backscattering
- Can be phenomenologically modelled by the Smith generalization

$$\tilde{\sigma}(\omega) = \frac{Ne^2\tau/m_{eff}}{1 - i\omega\tau} \left[1 + \sum_{n=1}^{\infty} \frac{c_n}{(1 - i\omega\tau)^n} \right]$$

- Generalized current response function $j(t)$. Truncate to first order
- Kramers-Kronig compatible (causal response function)
- Parameter c : degree of backscattering
- Parameter c : reflection coefficient at boundary
- Parameter c : first-order Taylor coefficient of generalized impulse response

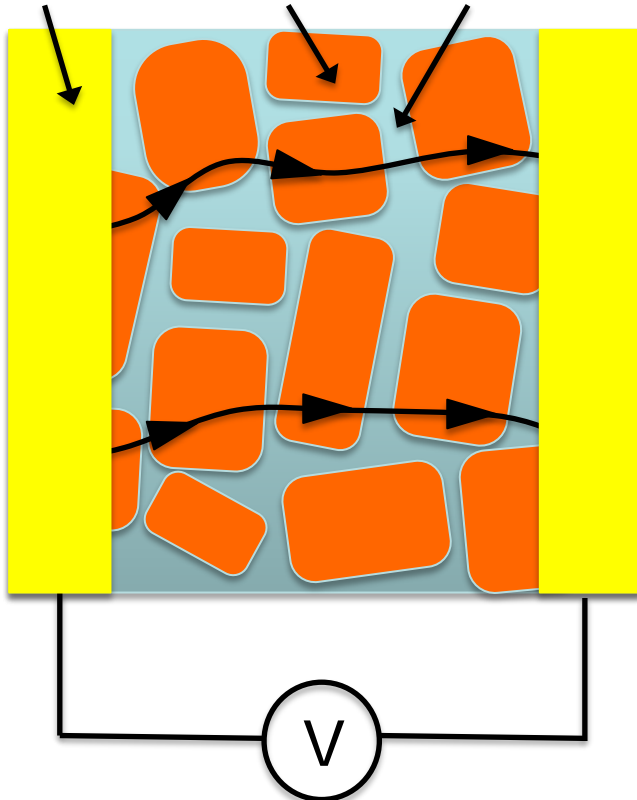
$$j(t) = f(t)e^{-t/\tau}, \quad c_n = \partial^n f / \partial t^n |_{t=0}$$



Conductivity in disordered media

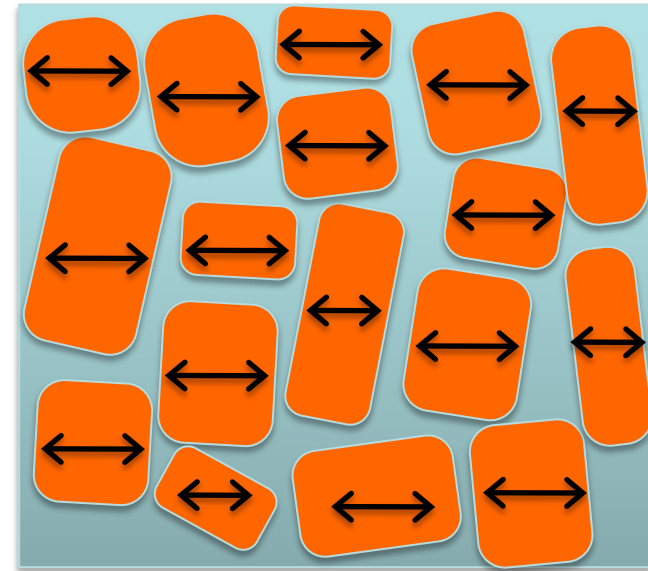
dc measurement

electrodes grains barriers



dc conductivity is determined by the highest barrier in conduction path

ac measurement



$$L_{\omega} = \sqrt{\frac{D}{\omega}}$$

Smaller conducting grains can contribute more to conductivity at higher ω .

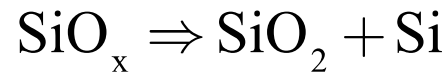


Silicon nanocrystals in glass

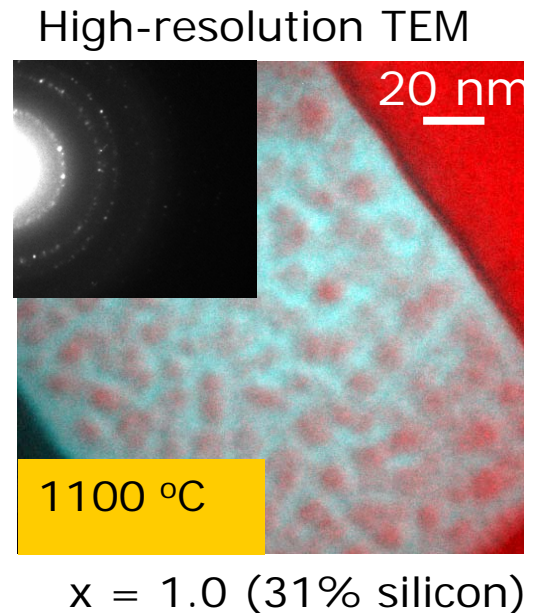
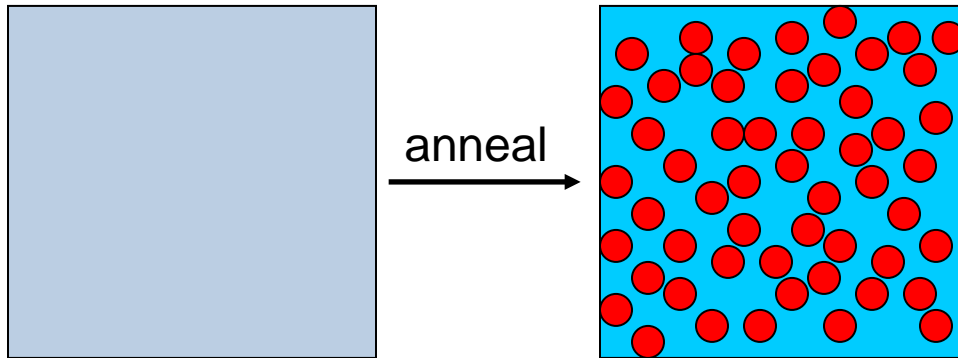
200 nm / 1 micron SiO_x on SiO_2 substrates

Annealed at 1100 C, 1 atm 95% N_2 + 5% H_2

⇒ Thermal decomposition of non-stoichiometric oxide: Si nanocrystals in SiO_2

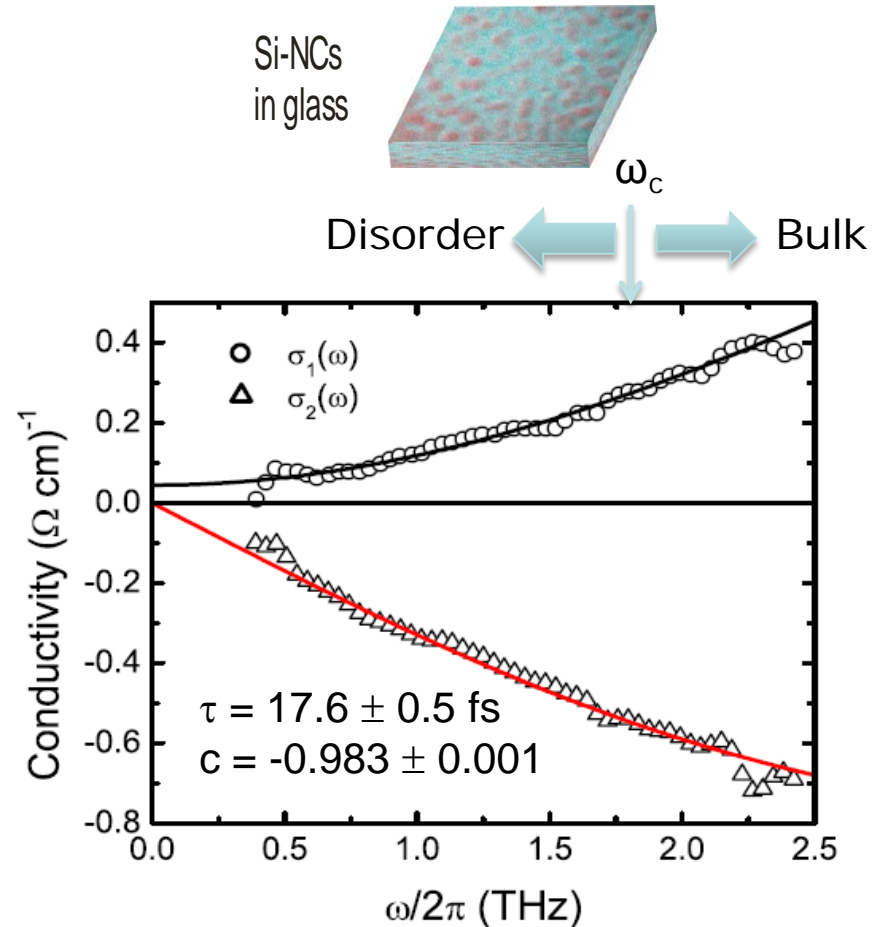
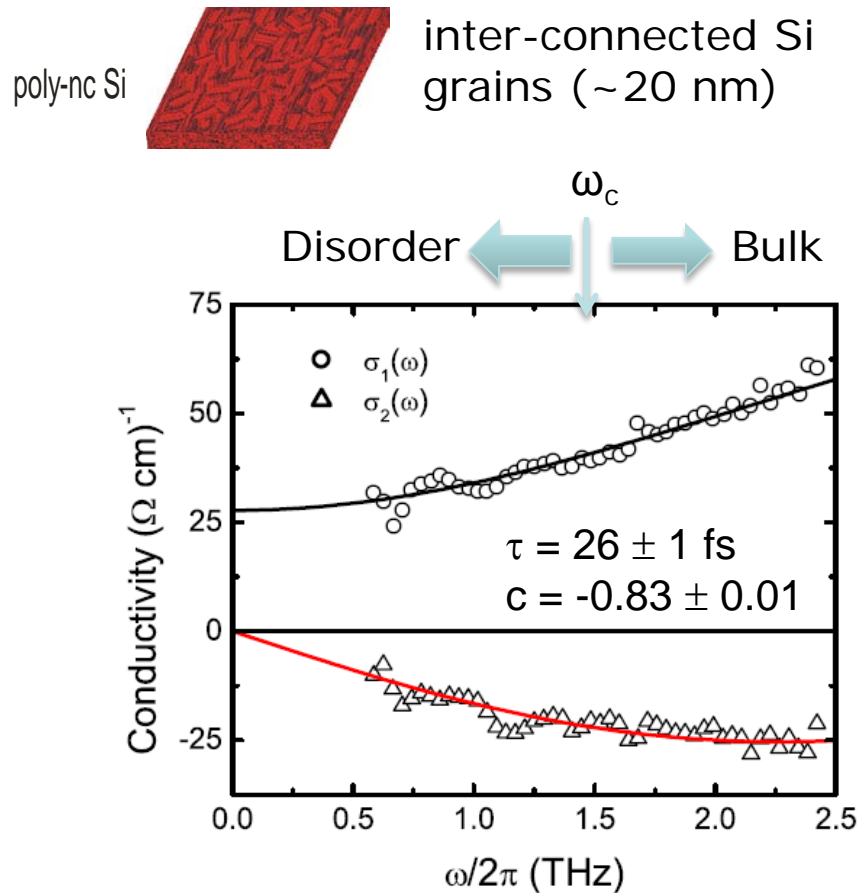


Variable NP density:
$$VF_{\text{Si}} = \frac{(2-x)V_{\text{mol}}^{\text{Si}}}{xV_{\text{mol}}^{\text{SiO}_2} + (2-x)V_{\text{mol}}^{\text{Si}}}$$





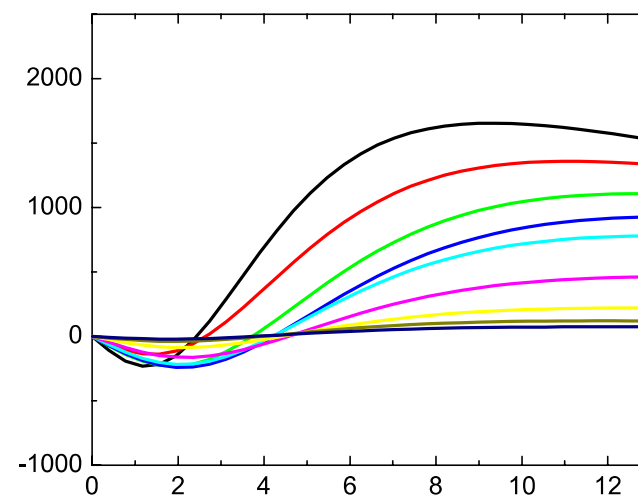
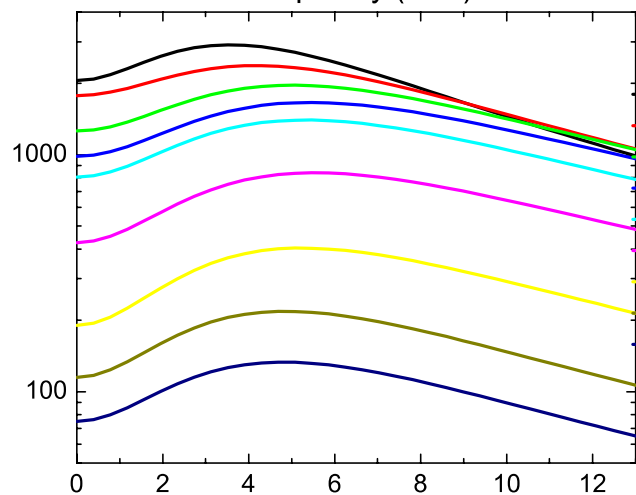
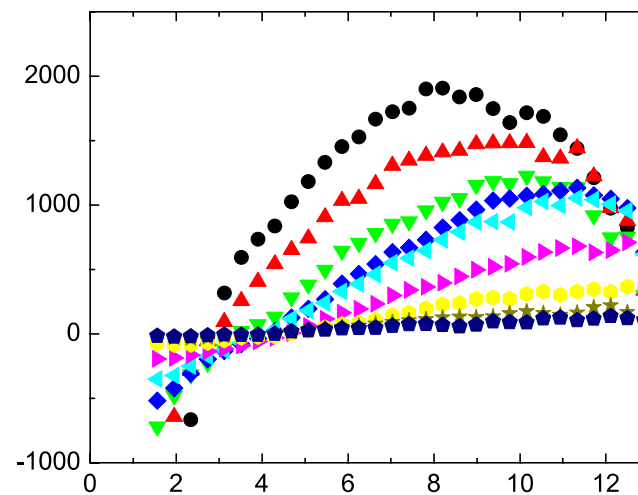
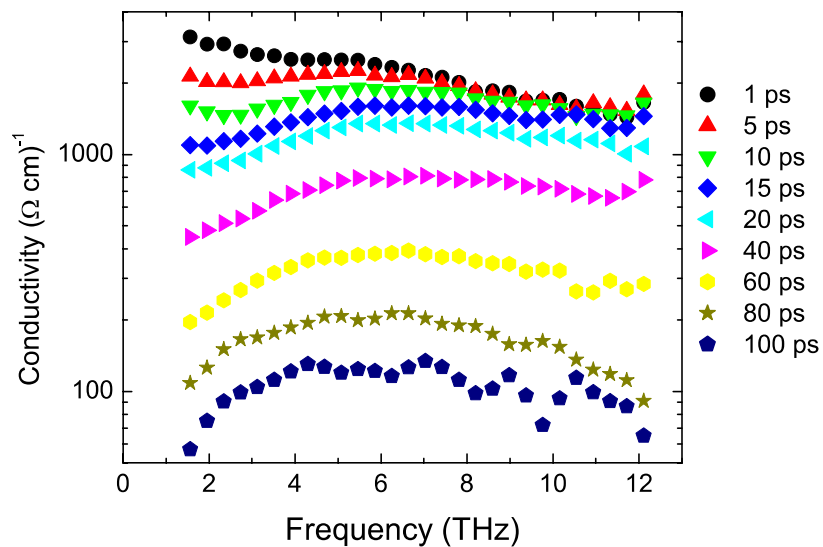
Low bandwidth measurements



Fused silica substrate cuts off transmission above 3 THz. **Reflection measurements**



Conductivity dynamics: $\text{SiO}_{x=0.2}$



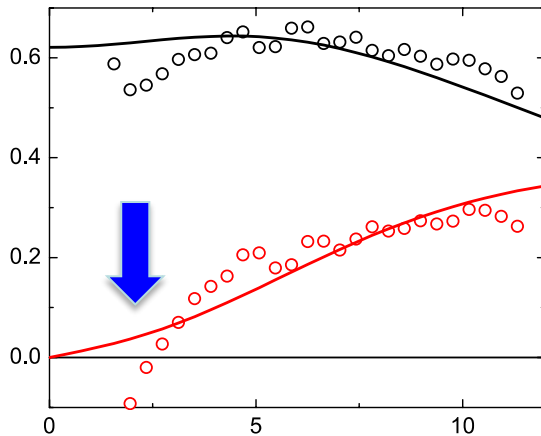


Drude behavior at early times

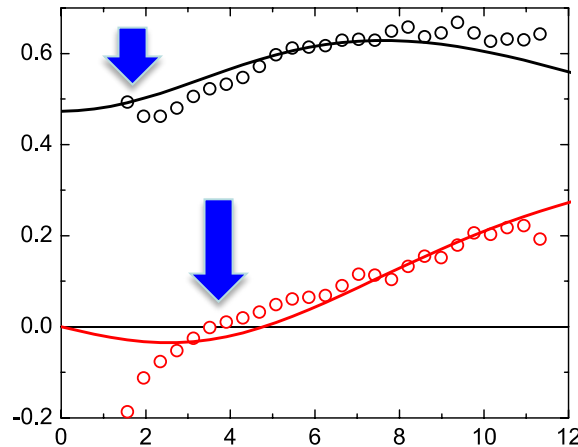
Evolution of conductivity: from Drude to partially localized response

$\text{SiO}_{x=0.6}$ (51% silicon)

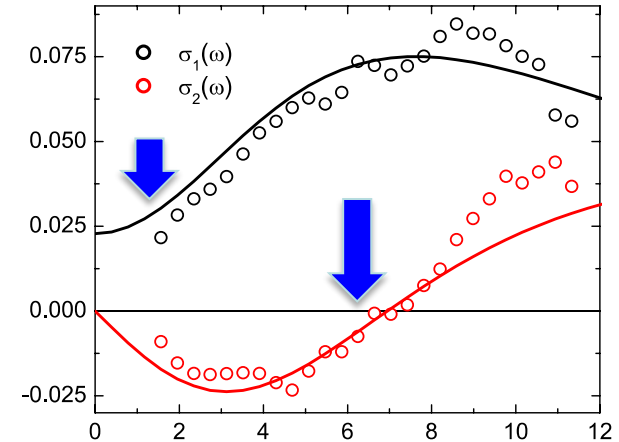
$t = 0.5 \text{ ps}$



$t = 2.0 \text{ ps}$



$t = 100 \text{ ps}$



Drude-like behavior at early times!
Carriers have yet to “feel” their confinement.

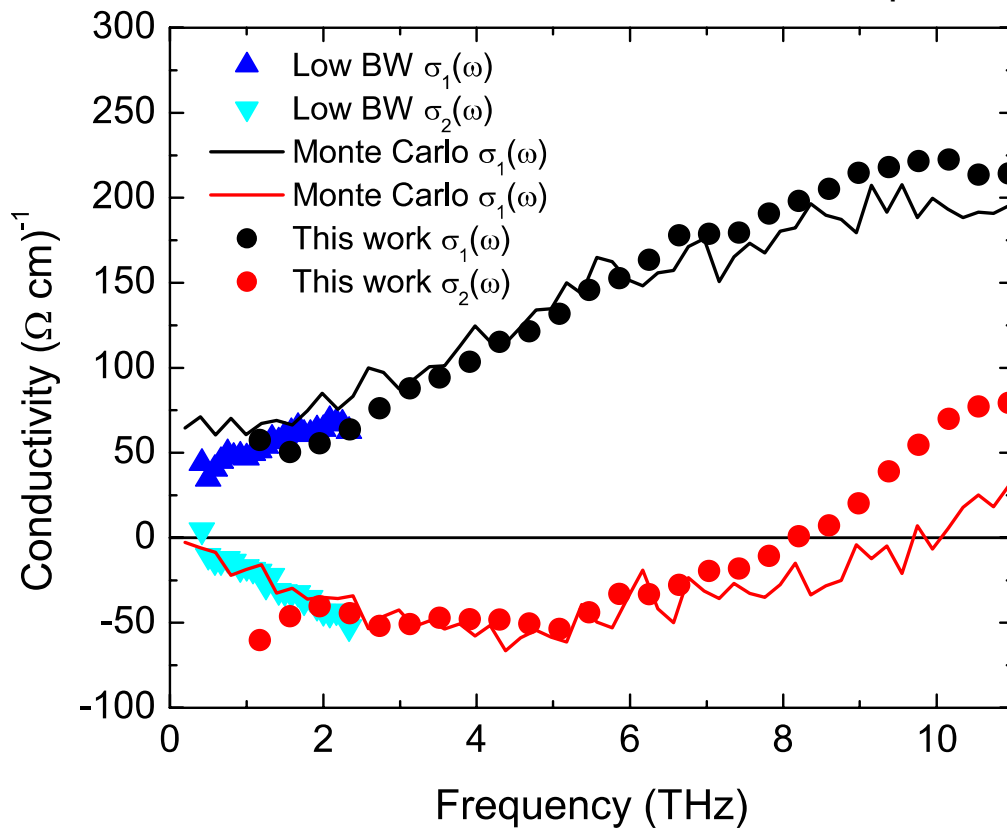
Partially localized
Long range conduction limited by SiO_2 barriers



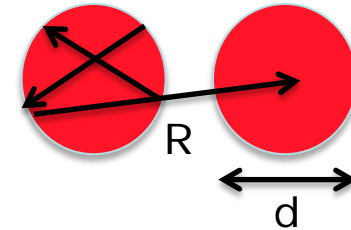
Agreement with previous work

$\text{SiO}_x = 0.6$ (51% silicon)

$t = +52 \text{ ps}$



Random sampling and no scaling of data



Monte Carlo parameters:

Reflection at particle boundary: $R = 85\%$

Particle diameter = 10 nm

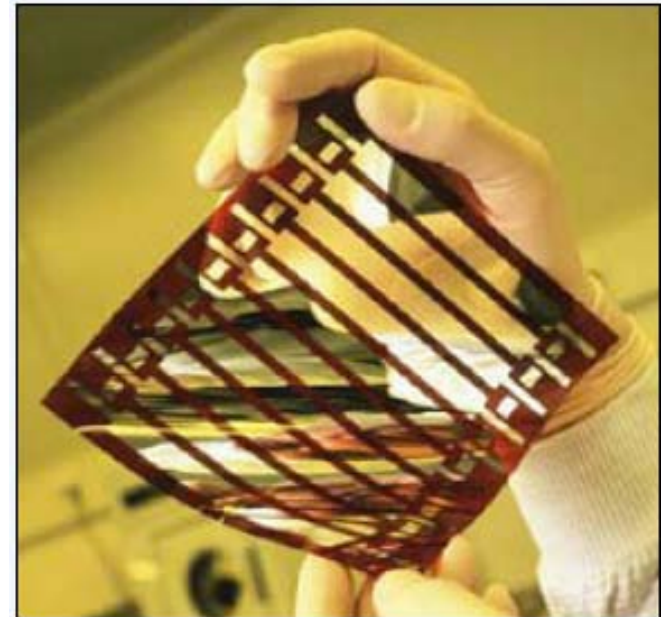
(courtesy of F. Hegmann group, Univ. Alberta, CA)

Excellent agreement with both low bandwidth work and Monte Carlo simulations



Plastic Photovoltaics

- Solution processed
- Lightweight
- Cheap to manufacture
- Compatible with large scale processing
- Fundamental excitation thought to be an exciton.
- Exciton $E_B > k_B T$
- Device performance depends on charge generation through exciton dissociation.
- **Ultrafast charge generation mechanism is a topic of huge debate, fueled by transient absorption and fs fluorescence upconversion.**
- **THz spectroscopy can contribute significantly here**



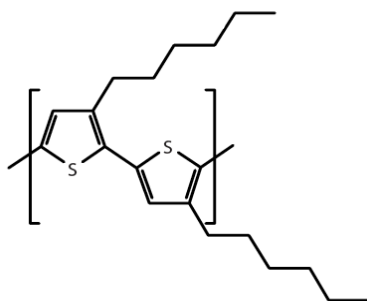
Organic materials promise inexpensive flexible solar fabric for powering personal electronics or for integration into buildings. Source: BRN Solar Report, Konarka



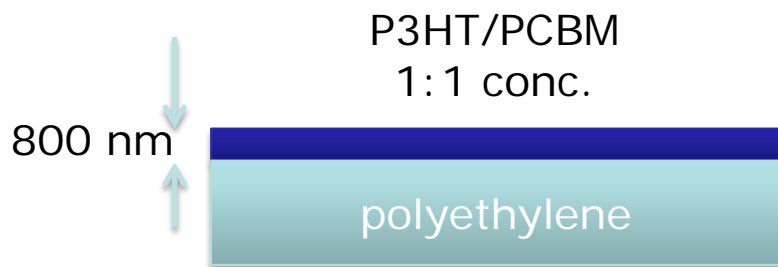
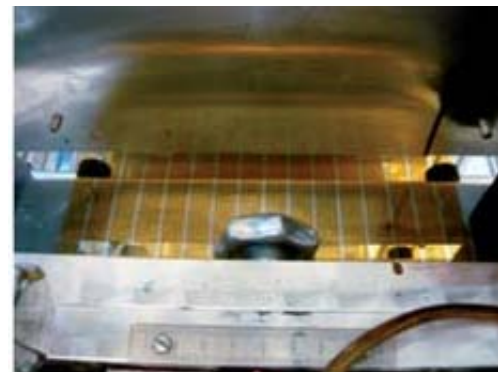
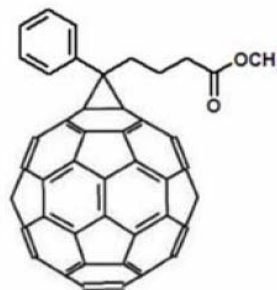
P3HT/PCBM roll-to-roll processed films



Poly-3-HexylThiophene



[6,6]-Phenyl-C61 Butyric acid Methyl ester



400 nm photoexcitation
Fluence = 570 $\mu\text{J}/\text{cm}^2$

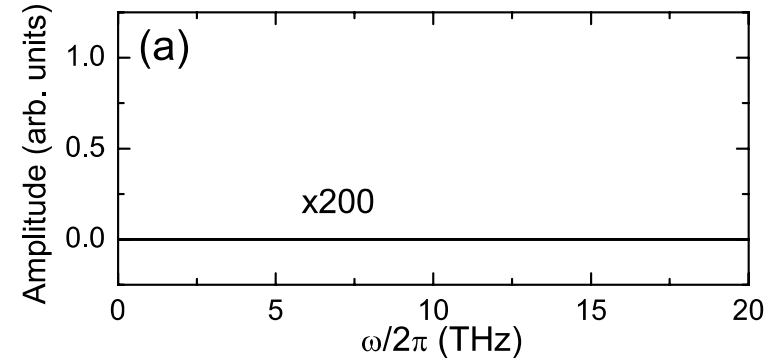


Measure on a real device-ready film!

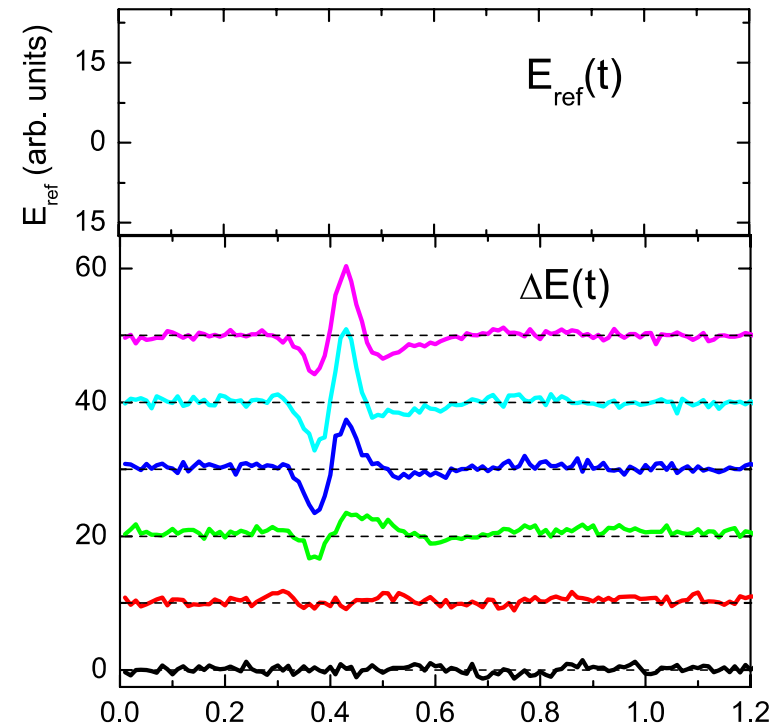


Differential THz scans at early times

Reference and differential spectra:



Reference pulse:



Differential pulses:

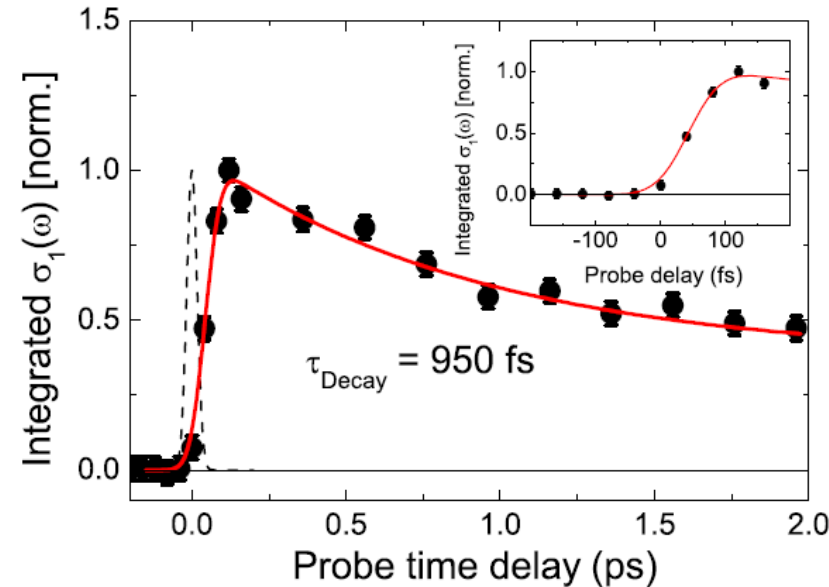
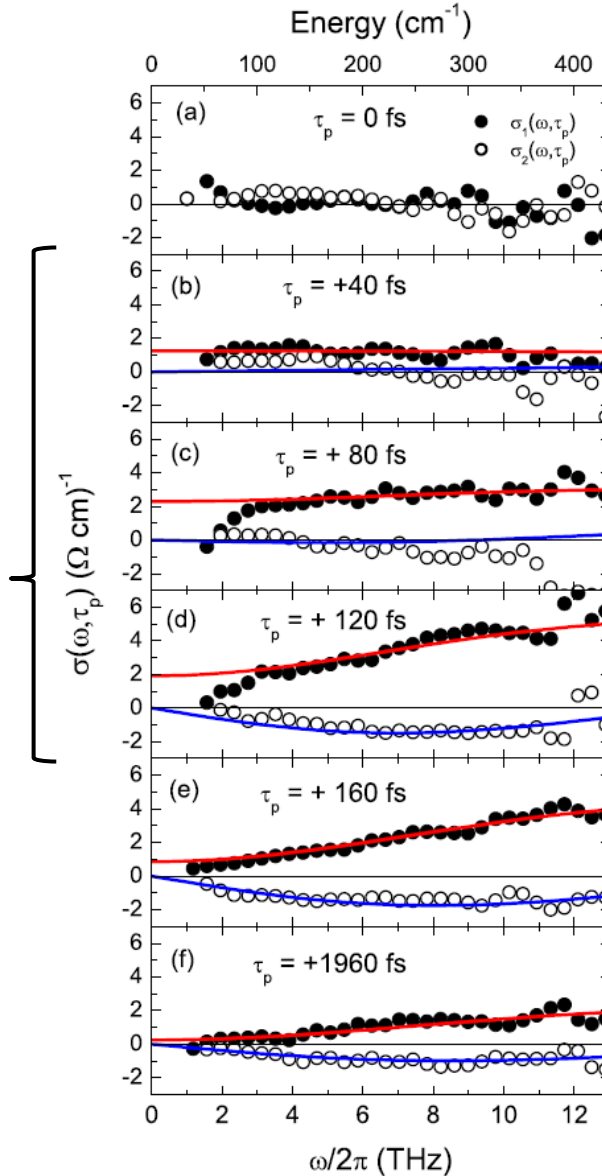


Sub-100 fs THz conductivity



Non-zero real conductivity is signature of mobile charges (delocalized polarons)

Free charges first 120 fs



Mobile charges created within 75 fs of excitation.
("Hot" exciton dissociation likely)

Then: re-trapping of charges
(~ 120 fs)

Later: 1/3 free charges
2/3 trapped charges

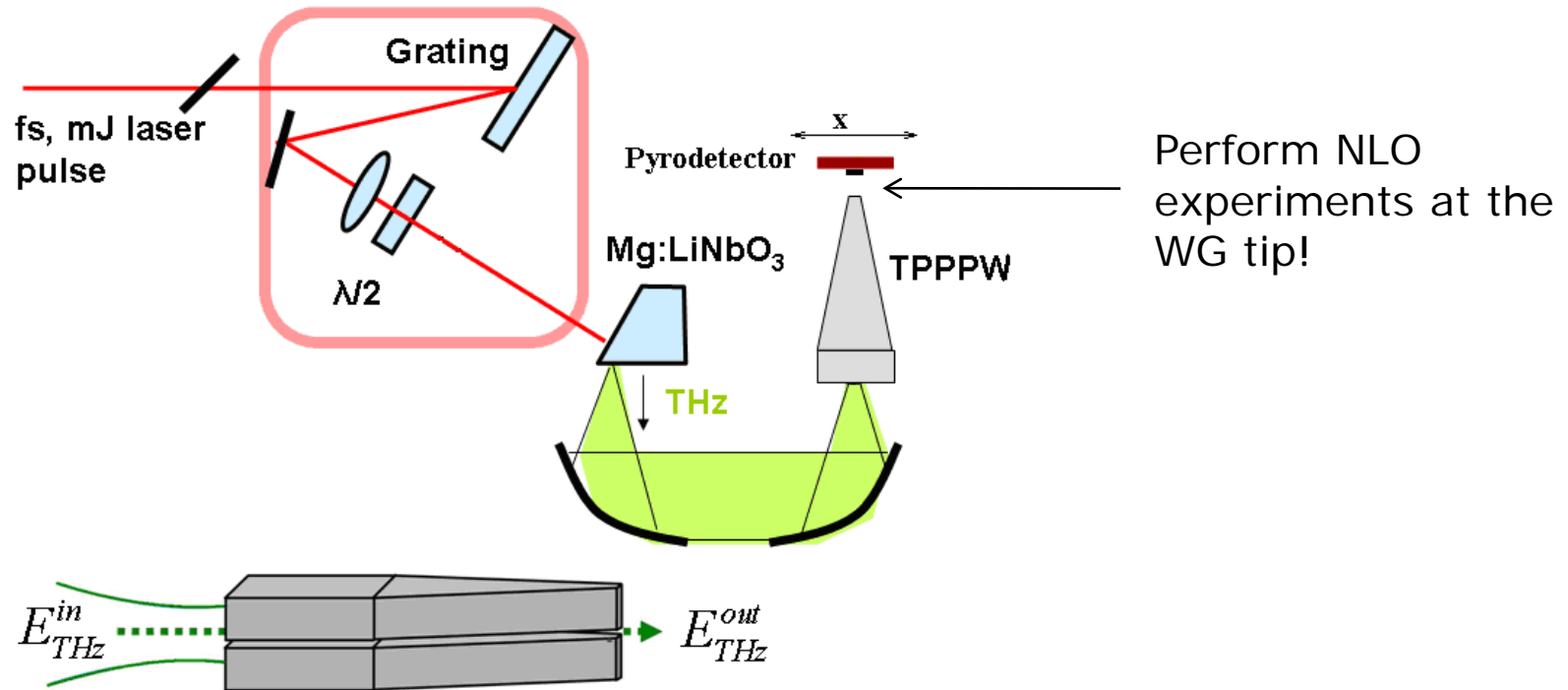


Field enhancement in waveguides

Challenge: Get high enough THz field strength for NLO at THz frequencies

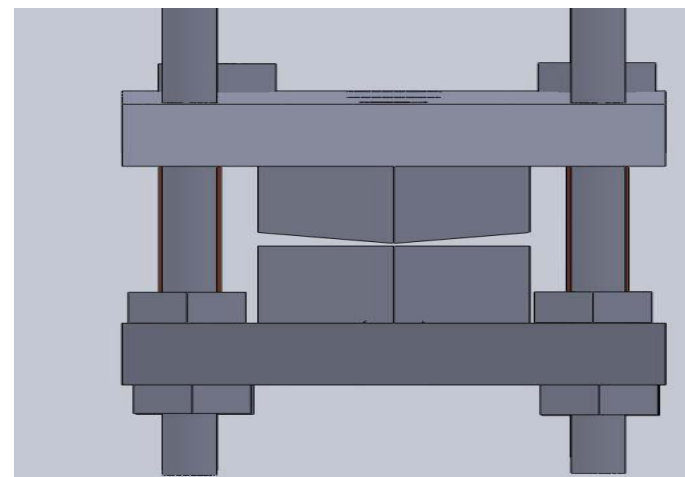
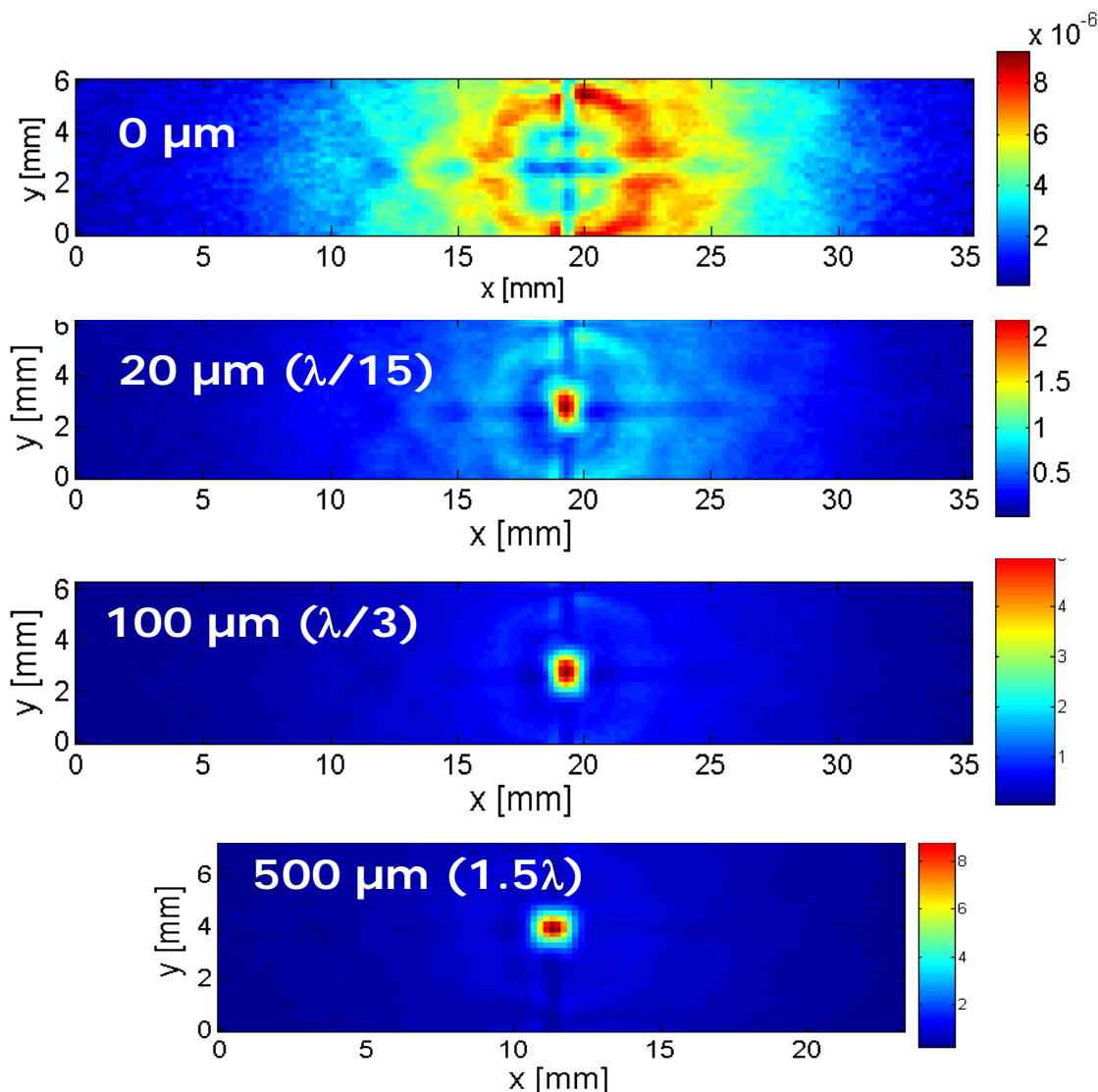
Here: Adiabatic compression of the field in a PPPW

Wavefront Control





Field compression



In contact:
no light through the tip

Sub- λ gaps:
significant field at the tip

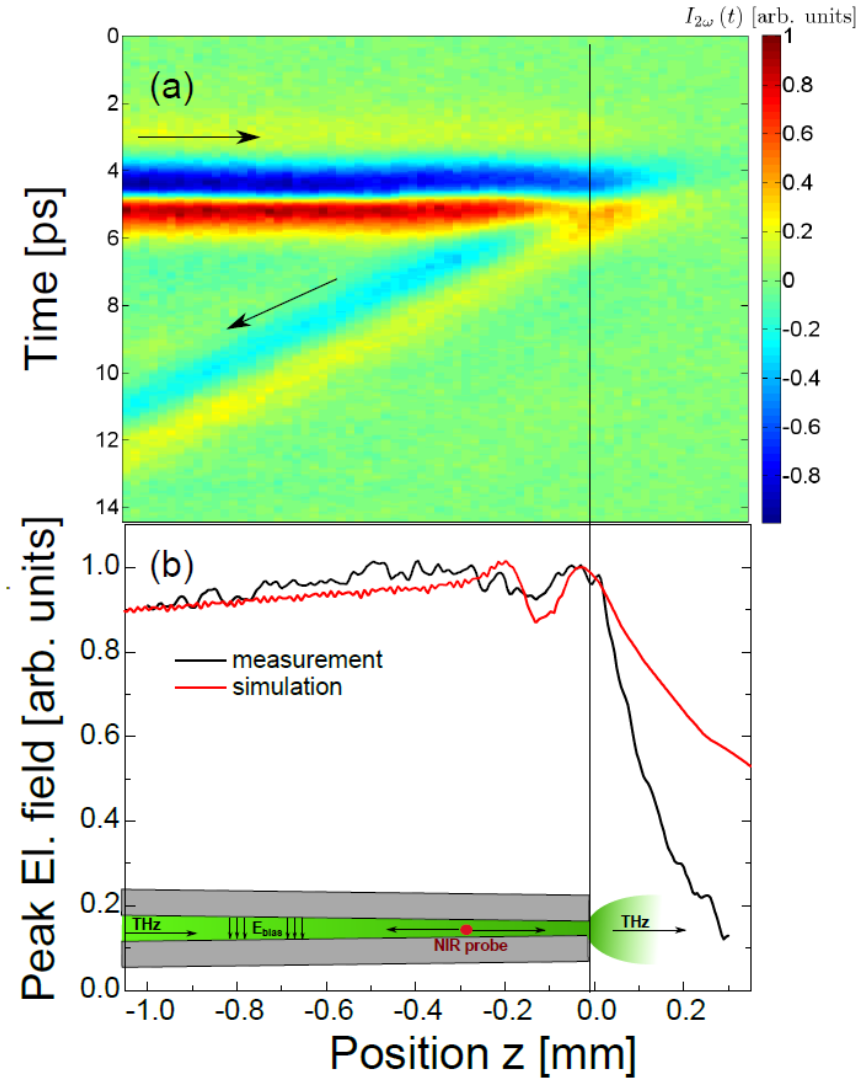
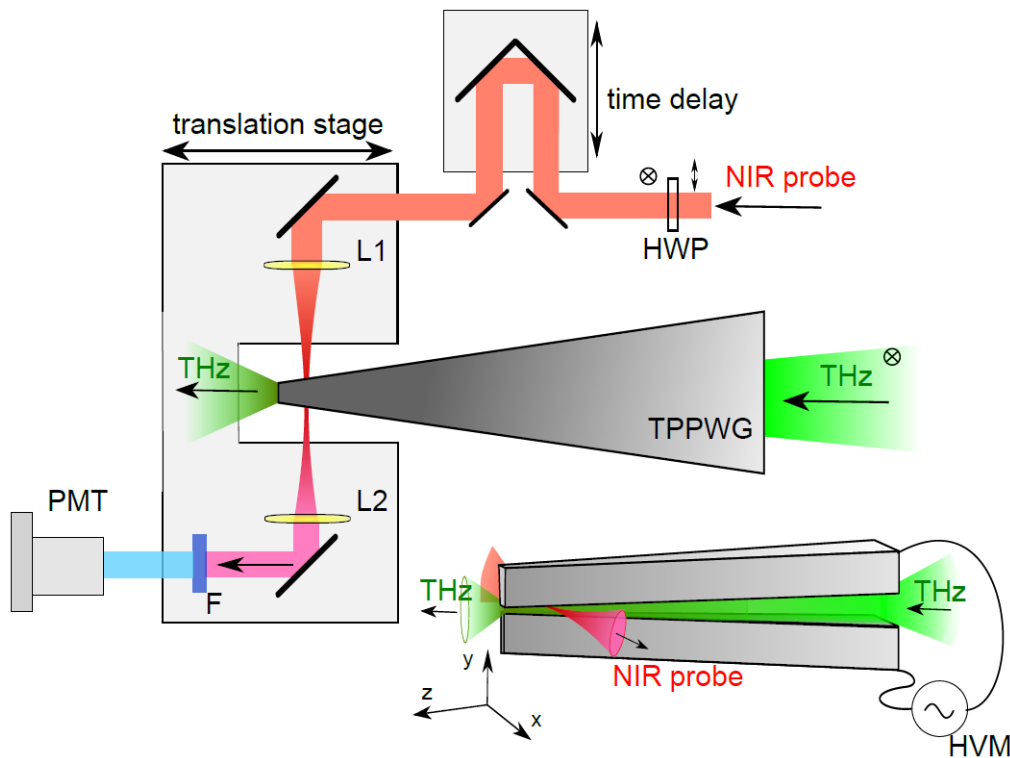
$>\lambda$ gaps:
very high transmission



Measurement of the THz field strength



- THz-enhanced SHG ($\chi^{(3)}$ process)
- Calibrated measurement of field strength





Calibration of E-field measurement

SHG in the presence of a THz field and a static field:

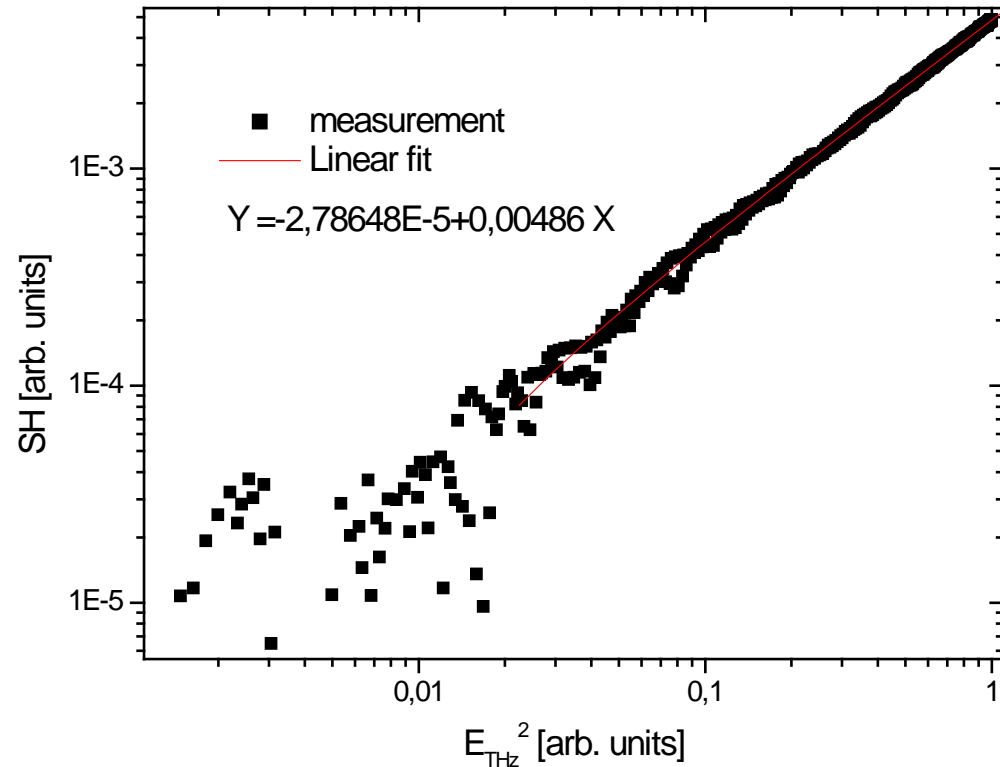
$$I_{2\omega} \propto \left(\chi^{(3)} I_{\omega} \right)^2 \left[\left(E_{THz} \right)^{(2)} + 2E_{bias} E_{THz} + \left(E_{bias} \right)^2 \right]$$

Modulate the THz field, use lock-in detection:

$$I_{2\omega} \propto \left(E_{THz} \right)^2 + 2E_{bias} E_{THz}$$

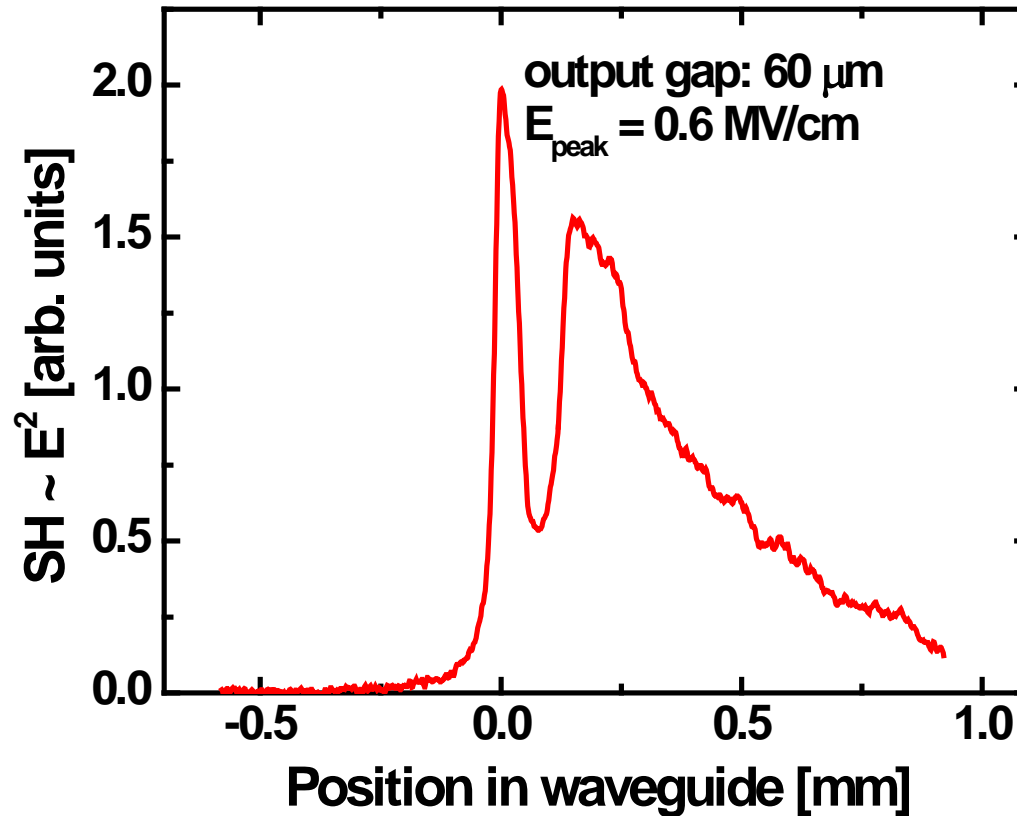
Modulate bias voltage, change of SH gives THz field strength:

$$dI_{2\omega} / dE_{bias} = 2E_{THz}$$





Results: $E_{\text{THz}} = 1.4 \text{ MV/cm}$ at WG tip



- Good agreement with full vectorial simulations
- $>1.4 \text{ MV/cm}$ obtained with $20 \mu\text{m}$ gap
- 100 kV/cm input field strength



Conclusions

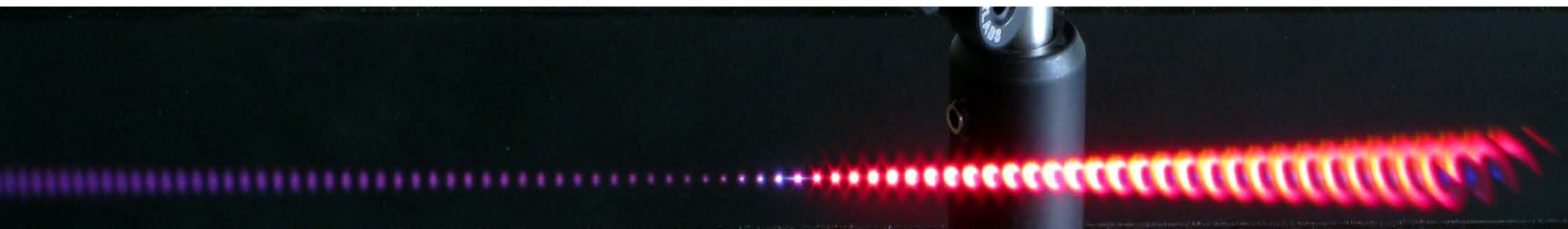
- THz spectroscopy is a good way to measure photoconductivity
- Complex conductivity spectrum is measured
- Conductivity models can be tested
- Disordered systems show clear non-Drude behaviour
- Ultrafast time resolution is important to reveal detailed dynamics

Acknowledgements:

Krzysztof Iwaszczuk (PhD student, DTU Fotonik)
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Prof. X.-C. Zhang (Rensselaer Polytechnic Institute)

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Danish Defence Acquisition and Logistics Organization
H. C. Ørsted Foundation





New THz journal

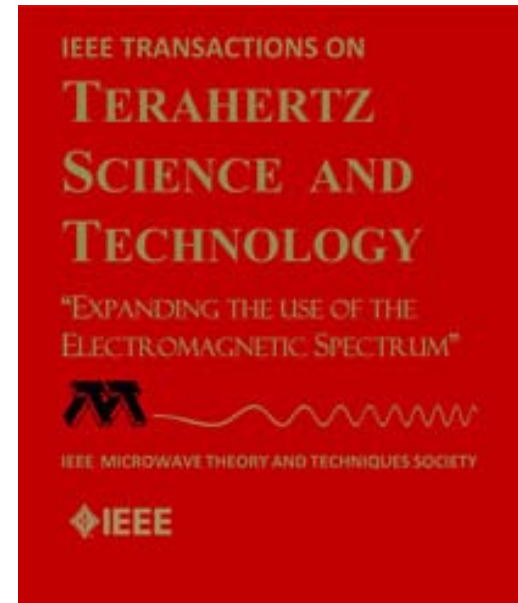


New THz journal from IEEE!

Each issue features interview articles with THz pioneers – March issue will host an interview with Nobel Laureate Bob Wilson.

Get a technical paper in the same issue!

Submissions at
<http://mc.manuscriptcentral.com/ieee-thz>





Upcoming conferences



**Submission Deadline:
December 5th**

<http://www.cleoconference.org/>

CLEO:2012

Technical Conference: 6-11 May 2012 Exposition: 8-10 May 2012
San Jose Convention Center, San Jose, CA, USA

**CLEO: QELS—
FUNDAMENTAL
SCIENCE**

**CLEO: SCIENCE
& INNOVATIONS**

**CLEO: APPLICATIONS
& TECHNOLOGY**



European Optical Society

Coherence for Europe®

**Submission opens:
January 16th 2012**

**Submission deadline:
February 17th 2012**

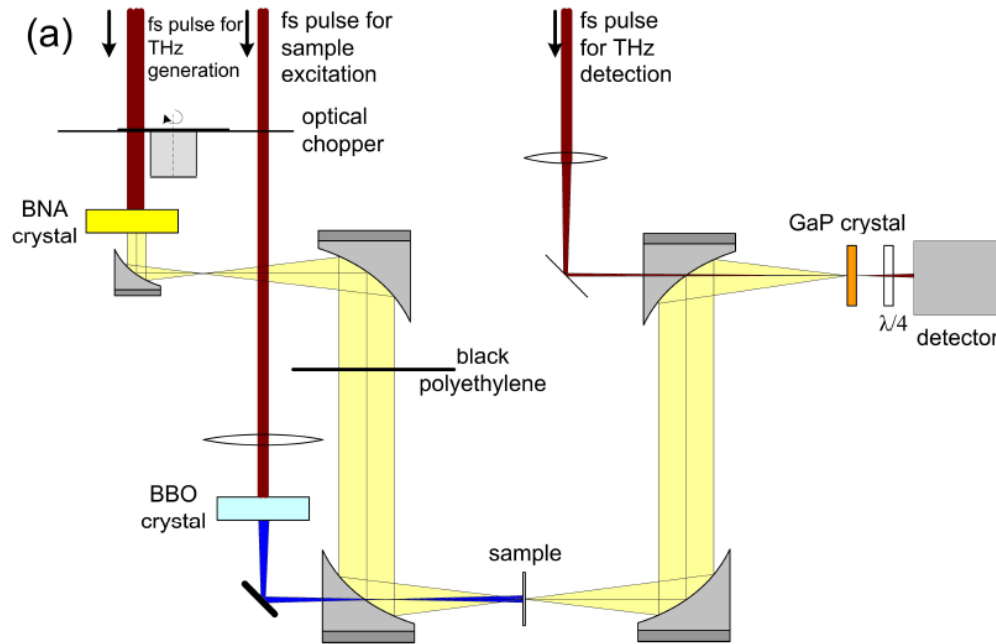
3rd EOS Topical Meeting

on THz Science & Technology (TST 2012)

17 - 20 June 2012

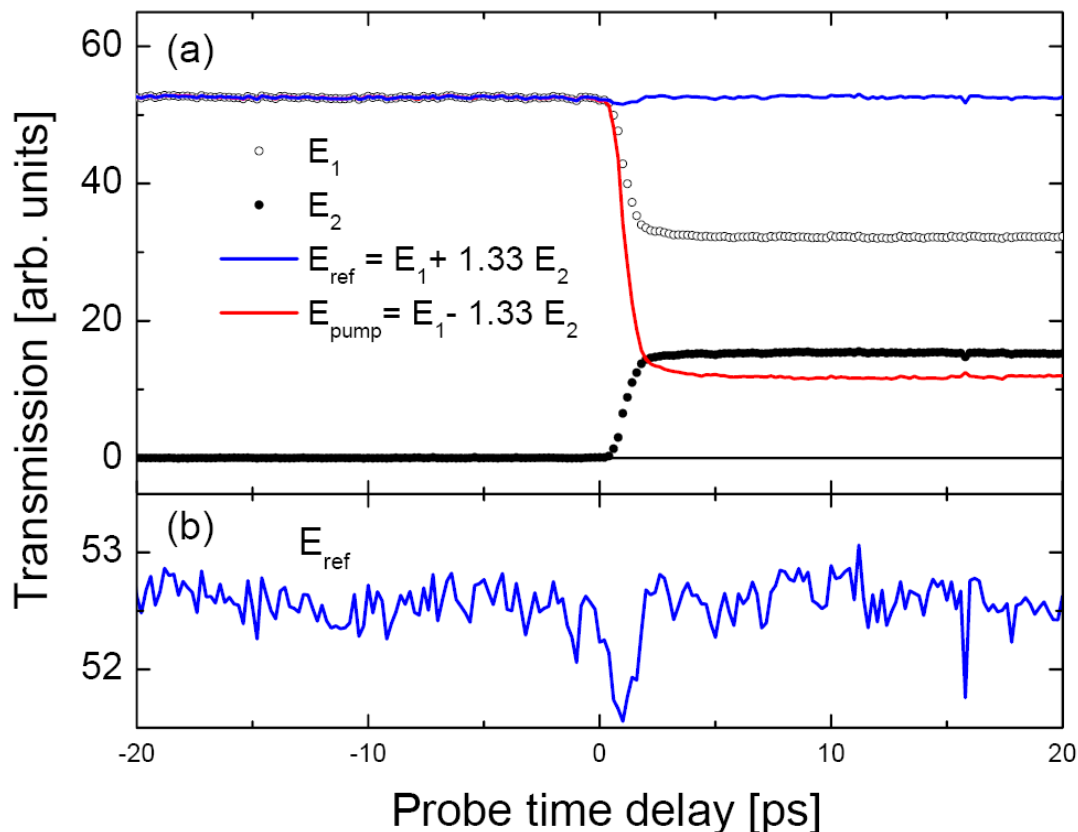
Kaiserstejnky Palace, Prague, Czech Republic

<http://www.myeos.org/events/tst2012>



- "Normal" THz time-domain spectroscopy
 - record reference data set ("sample OUT", or "optical pump OFF")
 - **then** record sample data set ("sample IN", or "optical pump ON")
- Alternative scheme for time-resolved pump-probe measurements:
 - Record reference and sample data **simultaneously**
 - minimizes influence of drift, power fluctuation, pointing stability issues, etc.

Dual lock-in scheme for data acquisition



$E_1(t)$ chopped at 333 Hz (2x167 Hz)
 $E_2(t)$ chopped at 500 Hz (3x167 Hz)

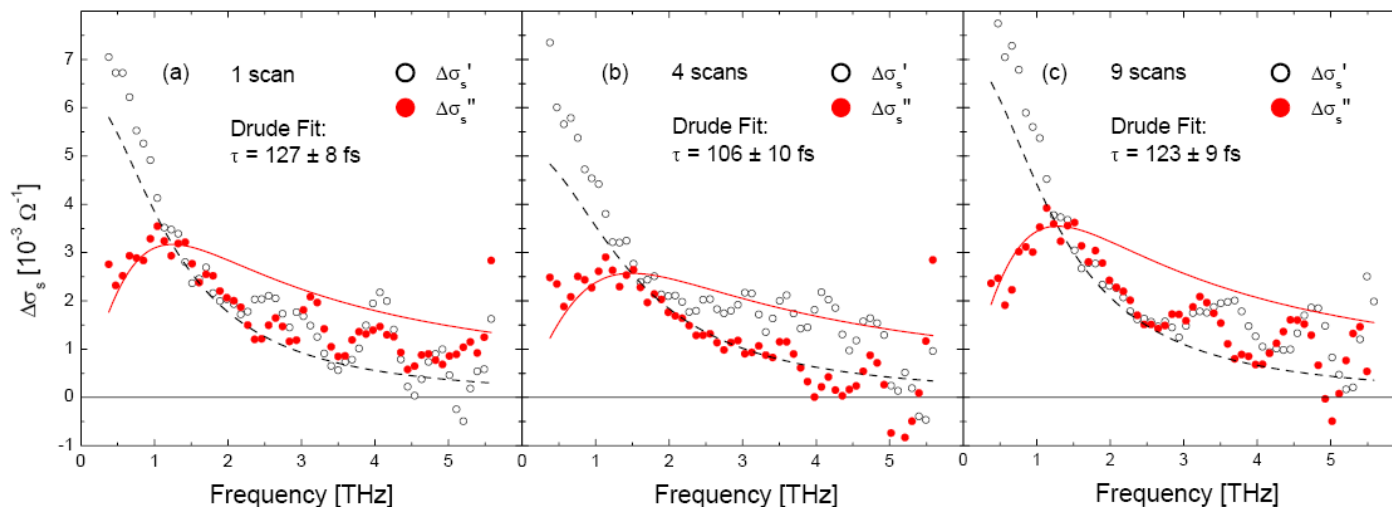


$$E_{ref}(t) = E_1(t) + AE_2(t)$$

$$E_{pump}(t) = E_1(t) - AE_2(t)$$

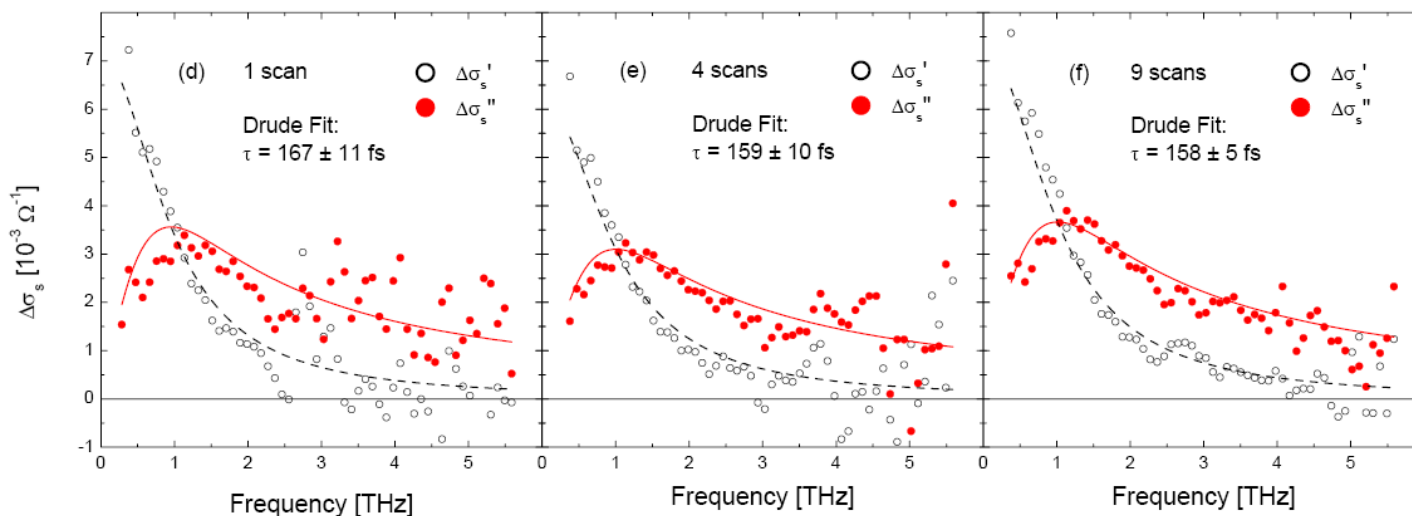
A is a constant which depends on the experiment

(specifically the Fourier components at $2f$ and $3f$ of the PD signal in the EO sampling system)



Sequential:

- Drude model cannot reproduce the spectra
- caused by minute (10-20 fs) jitter
- Experiment was placed in a room with poor temperature stability



Simultaneous:

- Drude model describes the spectra well
- no effect of jitter
- identical experimental conditions
- Scan time reduced by factor 2